## FAIRCHILD

SEMICONDUCTOR®

# FSAM20SH60A

## SPM<sup>™</sup> (Smart Power Module)

### **General Description**

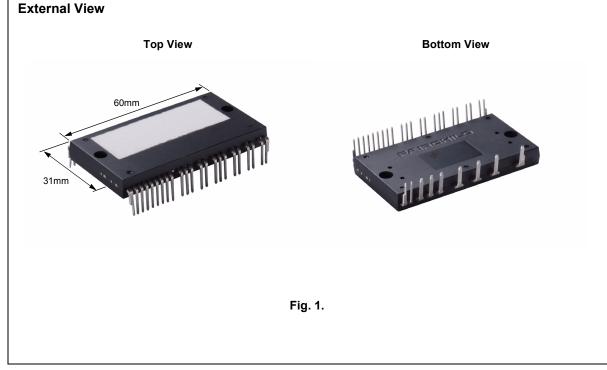
FSAM20SH60A is an advanced smart power module (SPM) that Fairchild has newly developed and designed to provide very compact and high performance ac motor drives mainly targeting high speed low-power inverterdriven application like washing machines. It combines optimized circuit protection and drive matched to low-loss IGBTs. Highly effective short-circuit current detection/ protection is realized through the use of advanced current sensing IGBT chips that allow continuous monitoring of the IGBTs current. System reliability is further enhanced by the built-in over-temperature monitoring and integrated undervoltage lock-out protection. The high speed built-in HVIC provides opto-coupler-less IGBT gate driving capability that further reduce the overall size of the inverter system design. In addition the incorporated HVIC facilitates the use of single-supply drive topology enabling the FSAM20SH60A to be driven by only one drive supply voltage without negative bias. Inverter current sensing application can be achieved due to the divided negative dc terminals.

#### **Features**

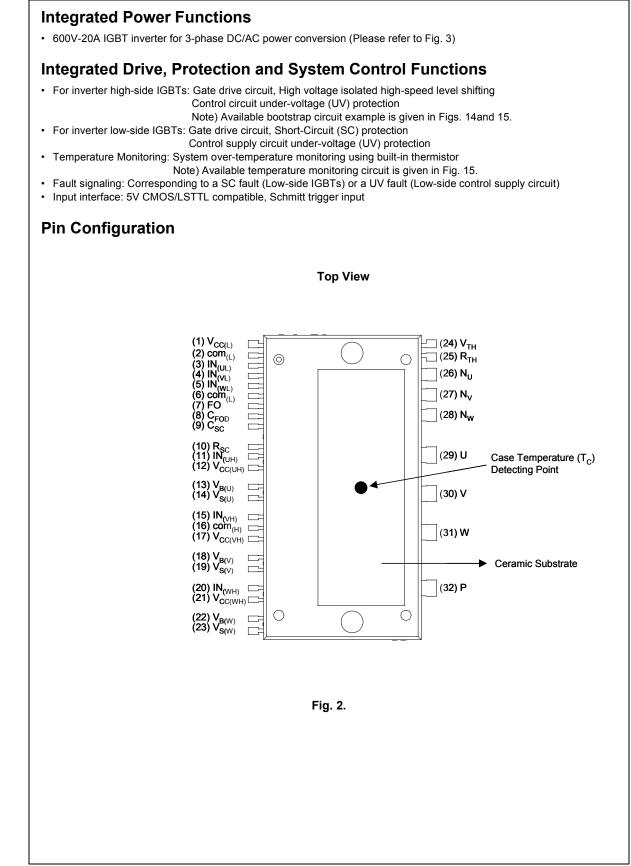
- UL Certified No. E209204
- 600V-20A 3-phase IGBT inverter bridge including control ICs for gate driving and protection
- Divided negative dc-link terminals for inverter current sensing applications
- · Single-grounded power supply due to built-in HVIC
- Typical switching frequency of 15kHz
- · Built-in thermistor for over-temperature monitoring
- Inverter power rating of 1.5kW / 100~253 Vac
- Isolation rating of 2500Vrms/min.
- Very low leakage current due to using ceramic substrate
- Adjustable current protection level by varying series resistor value with sense-IGBTs

### Applications

- AC 100V ~ 253V 3-phase inverter drive for small power (1.5kW) ac motor drives
- Home appliances applications requiring high switching frequency operation like washing machines drive system
  - Application ratings:
  - Power : 1.5kW / 100~253 Vac
  - Switching frequency : Typical 15kHz (PWM Control)
  - 100% load current : 8A (Irms)
  - 150% load current : 12A (Irms) for 1 minute



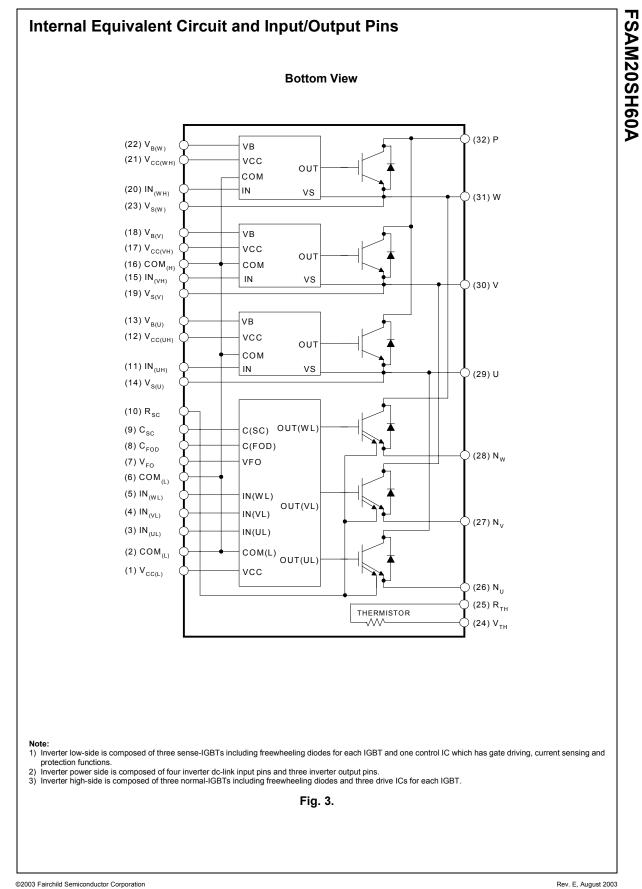
FSAM20SH60A



$\begin{array}{c c c c c c c c c c c c c c c c c c c $
2 $COM_{(L)}$ Low-side Common Supply Ground3 $IN_{(UL)}$ Signal Input for Low-side U Phase4 $IN_{(VL)}$ Signal Input for Low-side V Phase5 $IN_{(WL)}$ Signal Input for Low-side W Phase6 $COM_{(L)}$ Low-side Common Supply Ground7 $V_{FO}$ Fault Output8 $C_{FOD}$ Capacitor for Fault Output Duration Time Selection9 $C_{SC}$ Capacitor (Low-pass Filter) for Short-Circuit Current Detection Input10 $R_{SC}$ Resistor for Short-Circuit Current Detection11 $IN_{(UH)}$ Signal Input for High-side U Phase12 $V_{CC(UH)}$ High-side Bias Voltage for U Phase IGBT Driving14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving15 $IN_{(VH)}$ Signal Input for High-side V Phase16 $COM_{(H)}$ High-side Common Supply Ground17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IGBT Driving18 $V_{B(V)}$ High-side Bias Voltage for V Phase IGBT Driving19 $V_{S(V)}$ High-side Bias Voltage Ground for V Phase IGBT Driving20 $IN_{(WH)}$ Signal Input for High-side W Phase
4 $ N_{(VL)} $ Signal Input for Low-side V Phase5 $ N_{(WL)} $ Signal Input for Low-side W Phase6 $COM_{(L)} $ Low-side Common Supply Ground7 $V_{FO} $ Fault Output8 $C_{FOD} $ Capacitor for Fault Output Duration Time Selection9 $C_{SC} $ Capacitor (Low-pass Filter) for Short-Circuit Current Detection Input10 $R_{SC} $ Resistor for Short-Circuit Current Detection11 $ N_{(UH)} $ Signal Input for High-side U Phase12 $V_{CC(UH)} $ High-side Bias Voltage for U Phase IGBT Driving14 $V_{S(U)} $ High-side Bias Voltage Ground for U Phase IGBT Driving15 $ N_{(VH)} $ Signal Input for High-side V Phase16 $COM_{(H)} $ High-side Bias Voltage for V Phase IGBT Driving17 $V_{CC(VH)} $ High-side Bias Voltage for V Phase IGBT Driving19 $V_{S(V)} $ High-side Bias Voltage for V Phase IGBT Driving20 $ N_{(WH)} $ Signal Input for High-side V Phase
4 $IN_{(VL)}$ Signal Input for Low-side V Phase5 $IN_{(WL)}$ Signal Input for Low-side W Phase6 $COM_{(L)}$ Low-side Common Supply Ground7 $V_{FO}$ Fault Output8 $C_{FOD}$ Capacitor for Fault Output Duration Time Selection9 $C_{SC}$ Capacitor (Low-pass Filter) for Short-Circuit Current Detection Input10 $R_{SC}$ Resistor for Short-Circuit Current Detection11 $IN_{(UH)}$ Signal Input for High-side U Phase12 $V_{CC(UH)}$ High-side Bias Voltage for U Phase IGBT Driving14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving15 $IN_{(VH)}$ Signal Input for High-side V Phase16 $COM_{(H)}$ High-side Common Supply Ground17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IGBT Driving18 $V_{B(V)}$ High-side Bias Voltage for V Phase IGBT Driving20 $IN_{(WH)}$ Signal Input for High-side V Phase
$\begin{array}{c c c c c c c c c c c c c c c c c c c $
6 $COM_{(L)}$ Low-side Common Supply Ground7 $V_{FO}$ Fault Output8 $C_{FOD}$ Capacitor for Fault Output Duration Time Selection9 $C_{SC}$ Capacitor (Low-pass Filter) for Short-Circuit Current Detection Input10 $R_{SC}$ Resistor for Short-Circuit Current Detection11 $IN_{(UH)}$ Signal Input for High-side U Phase12 $V_{CC(UH)}$ High-side Bias Voltage for U Phase IC13 $V_{B(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase15 $IN_{(VH)}$ Signal Input for High-side V Phase16 $COM_{(H)}$ High-side Bias Voltage for V Phase IC17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IC18 $V_{B(V)}$ High-side Bias Voltage for V Phase IGBT Driving19 $V_{S(V)}$ High-side Bias Voltage Ground for V Phase IGBT Driving20 $IN_{(WH)}$ Signal Input for High-side W Phase
8 $C_{FOD}$ Capacitor for Fault Output Duration Time Selection9 $C_{SC}$ Capacitor (Low-pass Filter) for Short-Circuit Current Detection Input10 $R_{SC}$ Resistor for Short-Circuit Current Detection11 $IN_{(UH)}$ Signal Input for High-side U Phase12 $V_{CC(UH)}$ High-side Bias Voltage for U Phase IC13 $V_{B(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase15 $IN_{(VH)}$ Signal Input for High-side V Phase16 $COM_{(H)}$ High-side Bias Voltage for V Phase IC17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IC18 $V_{B(V)}$ High-side Bias Voltage for V Phase IGBT Driving20 $IN_{(WH)}$ Signal Input for High-side W Phase
8 $C_{FOD}$ Capacitor for Fault Output Duration Time Selection9 $C_{SC}$ Capacitor (Low-pass Filter) for Short-Circuit Current Detection Input10 $R_{SC}$ Resistor for Short-Circuit Current Detection11 $IN_{(UH)}$ Signal Input for High-side U Phase12 $V_{CC(UH)}$ High-side Bias Voltage for U Phase IC13 $V_{B(U)}$ High-side Bias Voltage for U Phase IGBT Driving14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving15 $IN_{(VH)}$ Signal Input for High-side V Phase16 $COM_{(H)}$ High-side Bias Voltage for V Phase IC17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IC18 $V_{B(V)}$ High-side Bias Voltage for V Phase IGBT Driving20 $IN_{(WH)}$ Signal Input for High-side V Phase
9 $C_{SC}$ Capacitor (Low-pass Filter) for Short-Circuit Current Detection Input10 $R_{SC}$ Resistor for Short-Circuit Current Detection11 $IN_{(UH)}$ Signal Input for High-side U Phase12 $V_{CC(UH)}$ High-side Bias Voltage for U Phase IC13 $V_{B(U)}$ High-side Bias Voltage for U Phase IGBT Driving14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving15 $IN_{(VH)}$ Signal Input for High-side V Phase16 $COM_{(H)}$ High-side Common Supply Ground17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IGBT Driving19 $V_{S(V)}$ High-side Bias Voltage Ground for V Phase IGBT Driving20 $IN_{(WH)}$ Signal Input for High-side W Phase
10 $R_{SC}$ Resistor for Short-Circuit Current Detection11 $IN_{(UH)}$ Signal Input for High-side U Phase12 $V_{CC(UH)}$ High-side Bias Voltage for U Phase IC13 $V_{B(U)}$ High-side Bias Voltage for U Phase IGBT Driving14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving15 $IN_{(VH)}$ Signal Input for High-side V Phase16 $COM_{(H)}$ High-side Common Supply Ground17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IGBT Driving18 $V_{B(V)}$ High-side Bias Voltage for V Phase IGBT Driving19 $V_{S(V)}$ High-side Bias Voltage Ground for V Phase IGBT Driving20 $IN_{(WH)}$ Signal Input for High-side W Phase
11IN <sub>(UH)</sub> Signal Input for High-side U Phase12 $V_{CC(UH)}$ High-side Bias Voltage for U Phase IC13 $V_{B(U)}$ High-side Bias Voltage for U Phase IGBT Driving14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving15IN <sub>(VH)</sub> Signal Input for High-side V Phase16 $COM_{(H)}$ High-side Common Supply Ground17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IC18 $V_{B(V)}$ High-side Bias Voltage for V Phase IGBT Driving20IN <sub>(WH)</sub> Signal Input for High-side W Phase
12 $V_{CC(UH)}$ High-side Bias Voltage for U Phase IC13 $V_{B(U)}$ High-side Bias Voltage for U Phase IGBT Driving14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving15 $IN_{(VH)}$ Signal Input for High-side V Phase16 $COM_{(H)}$ High-side Common Supply Ground17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IC18 $V_{B(V)}$ High-side Bias Voltage for V Phase IGBT Driving20 $IN_{(WH)}$ Signal Input for High-side W Phase
13 $V_{B(U)}$ High-side Bias Voltage for U Phase IGBT Driving14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving15 $IN_{(VH)}$ Signal Input for High-side V Phase16 $COM_{(H)}$ High-side Common Supply Ground17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IC18 $V_{B(V)}$ High-side Bias Voltage for V Phase IGBT Driving19 $V_{S(V)}$ High-side Bias Voltage Ground for V Phase IGBT Driving20 $IN_{(WH)}$ Signal Input for High-side W Phase
14 $V_{S(U)}$ High-side Bias Voltage Ground for U Phase IGBT Driving         15 $IN_{(VH)}$ Signal Input for High-side V Phase         16 $COM_{(H)}$ High-side Common Supply Ground         17 $V_{CC(VH)}$ High-side Bias Voltage for V Phase IC         18 $V_{B(V)}$ High-side Bias Voltage for V Phase IGBT Driving         19 $V_{S(V)}$ High-side Bias Voltage Ground for V Phase IGBT Driving         20 $IN_{(WH)}$ Signal Input for High-side W Phase
15         IN <sub>(VH)</sub> Signal Input for High-side V Phase           16         COM <sub>(H)</sub> High-side Common Supply Ground           17         V <sub>CC(VH)</sub> High-side Bias Voltage for V Phase IC           18         V <sub>B(V)</sub> High-side Bias Voltage for V Phase IGBT Driving           19         V <sub>S(V)</sub> High-side Bias Voltage Ground for V Phase IGBT Driving           20         IN <sub>(WH)</sub> Signal Input for High-side W Phase
16         COM <sub>(H)</sub> High-side Common Supply Ground           17         V <sub>CC(VH)</sub> High-side Bias Voltage for V Phase IC           18         V <sub>B(V)</sub> High-side Bias Voltage for V Phase IGBT Driving           19         V <sub>S(V)</sub> High-side Bias Voltage Ground for V Phase IGBT Driving           20         IN <sub>(WH)</sub> Signal Input for High-side W Phase
17     V <sub>CC(VH)</sub> High-side Bias Voltage for V Phase IC       18     V <sub>B(V)</sub> High-side Bias Voltage for V Phase IGBT Driving       19     V <sub>S(V)</sub> High-side Bias Voltage Ground for V Phase IGBT Driving       20     IN <sub>(WH)</sub> Signal Input for High-side W Phase
18         V <sub>B(V)</sub> High-side Bias Voltage for V Phase IGBT Driving           19         V <sub>S(V)</sub> High-side Bias Voltage Ground for V Phase IGBT Driving           20         IN <sub>(WH)</sub> Signal Input for High-side W Phase
19         V <sub>S(V)</sub> High-side Bias Voltage Ground for V Phase IGBT Driving           20         IN <sub>(WH)</sub> Signal Input for High-side W Phase
20 IN(WH) Signal Input for High-side W Phase
22 V <sub>B(W)</sub> High-side Bias Voltage for W Phase IGBT Driving
23 V <sub>S(W)</sub> High-side Bias Voltage Ground for W Phase IGBT Driving
25         R <sub>TH</sub> Series Resistor for the Use of Thermistor (Temperature Detection)           26         N <sub>U</sub> Negative DC–Link Input for U Phase
27 N <sub>V</sub> Negative DC-Link Input for V Phase
28         N <sub>W</sub> Negative DC-Link Input for W Phase           29         U         Output for U Phase
30 V Output for V Phase
31 W Output for W Phase
32 P Positive DC–Link Input

Rev. E, August 2003

FSAM20SH60A



# Absolute Maximum Ratings (T<sub>J</sub> = 25°C, Unless Otherwise Specified)

## **Inverter Part**

Item	Symbol	Condition	Rating	Unit	
Supply Voltage	V <sub>PN</sub>	Applied between P- N <sub>U</sub> , N <sub>V</sub> , N <sub>W</sub>	450	V	
Supply Voltage (Surge)	V <sub>PN(Surge)</sub>	Applied between P- $N_U$ , $N_V$ , $N_W$	500	V	
Collector-Emitter Voltage	V <sub>CES</sub>		600	V	
Each IGBT Collector Current	± I <sub>C</sub>	$T_{\rm C} = 25^{\circ}{\rm C}$	20	Α	
Each IGBT Collector Current	± I <sub>C</sub>	$T_{\rm C}$ = 100°C	14	Α	
Each IGBT Collector Current (Peak)	± I <sub>CP</sub>	T <sub>C</sub> = 25°C, Instantaneous Value (Pulse)	40	A	
Collector Dissipation	P <sub>C</sub>	T <sub>C</sub> = 25°C per One Chip	59	W	
Operating Junction Temperature	TJ	(Note 1)	-20 ~ 125	°C	

Note: 1. It would be recommended that the average junction temperature should be limited to  $T_J \le 125^{\circ}C$  (@ $T_C \le 100^{\circ}C$ ) in order to guarantee safe operation.

## **Control Part**

Item	Symbol	Condition	Rating	Unit
Control Supply Voltage	V <sub>CC</sub>	Applied between $V_{CC(UH)}$ , $V_{CC(VH)}$ , $V_{CC(WH)}$ - $COM_{(H)}$ , $V_{CC(L)}$ - $COM_{(L)}$	20	V
High-side Control Bias Voltage	V <sub>BS</sub>	Applied between V <sub>B(U)</sub> - V <sub>S(U)</sub> , V <sub>B(V)</sub> - V <sub>S(V)</sub> , V <sub>B(W)</sub> - V <sub>S(W)</sub>	20	V
Input Signal Voltage	V <sub>IN</sub>	Applied between $IN_{(UH)}$ , $IN_{(VH)}$ , $IN_{(WH)}$ - $COM_{(H)}$ $IN_{(UL)}$ , $IN_{(VL)}$ , $IN_{(WL)}$ - $COM_{(L)}$	-0.3 ~ V <sub>CC</sub> +0.3	V
Fault Output Supply Voltage	V <sub>FO</sub>	Applied between V <sub>FO</sub> - COM <sub>(L)</sub>	-0.3 ~ V <sub>CC</sub> +0.3	V
Fault Output Current	I <sub>FO</sub>	Sink Current at V <sub>FO</sub> Pin	5	mA
Current Sensing Input Voltage	V <sub>SC</sub>	Applied between C <sub>SC</sub> - COM <sub>(L)</sub>	-0.3 ~ V <sub>CC</sub> +0.3	V

## **Total System**

Item	Symbol	Condition	Rating	Unit
Self Protection Supply Voltage Limit (Short-Circuit Protection Capability)	V <sub>PN(PROT)</sub>	V <sub>CC</sub> = V <sub>BS</sub> = 13.5 ~ 16.5V T <sub>J</sub> = 25°C, Non-repetitive, less than 6μs	400	V
Module Case Operation Temperature	Т <sub>С</sub>	Note Fig.2	-20 ~ 100	°C
Storage Temperature	T <sub>STG</sub>		-20 ~ 125	°C
Isolation Voltage	V <sub>ISO</sub>	60Hz, Sinusoidal, AC 1 minute, Connection Pins to Heat-sink Plate	2500	V <sub>rms</sub>

# **Absolute Maximum Ratings**

## **Thermal Resistance**

Item	Symbol	Condition	Min.	Тур.	Max.	Unit
Junction to Case Thermal Resistance	R <sub>th(j-c)Q</sub>	Each IGBT under Inverter Operating Condition		-	2.1	°C/W
	R <sub>th(j-c)F</sub>	Each FWDi under Inverter Operating Condition -		-	3.3	°C/W
Contact Thermal Resistance	R <sub>th(c-f)</sub>	Ceramic Substrate (per 1 Module) C Thermal Grease Applied (Note 3)		0.06	°C/W	

 $\begin{array}{l} \textbf{Note:}\\ \textbf{2. For the measurement point of case temperature(T_C), please refer to Fig. 2.\\ \textbf{3. The thickness of thermal grease should not be more than 100um.} \end{array}$ 

# **Electrical Characteristics** (T<sub>J</sub> = 25°C, Unless Otherwise Specified)

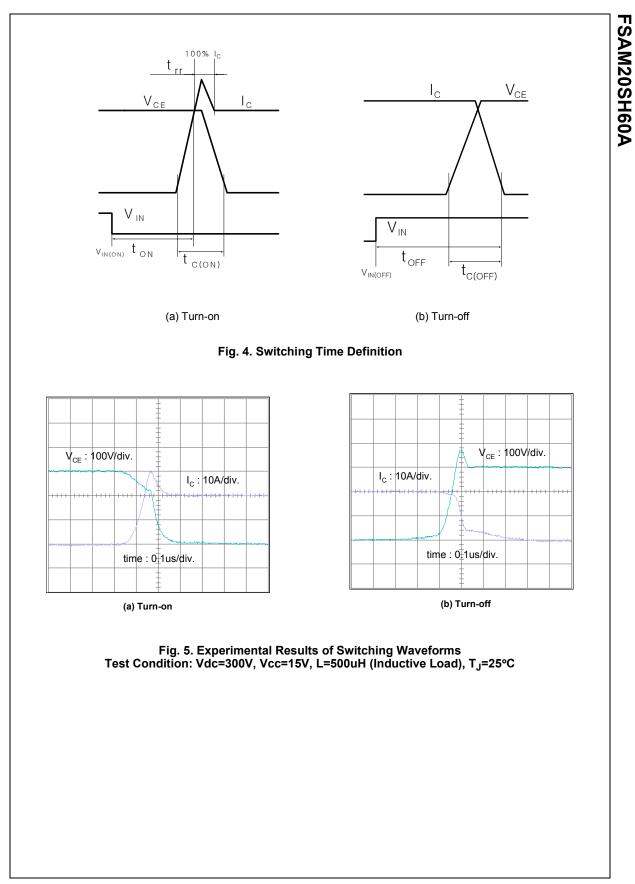
## **Inverter Part**

Item	Symbol	Conditio	on	Min.	Тур.	Max.	Unit
Collector - Emitter Saturation Voltage	V <sub>CE(SAT)</sub>	$V_{CC} = V_{BS} = 15V$ $V_{IN} = 0V$	I <sub>C</sub> = 20A, T <sub>J</sub> = 25°C	-	-	2.5	V
FWDi Forward Voltage	V <sub>FM</sub>	V <sub>IN</sub> = 5V	$I_{C} = 20A, T_{J} = 25^{\circ}C$	-	-	2.5	V
Switching Times	t <sub>ON</sub>	$V_{PN} = 300V, V_{CC} = V_{BS} = 15V$ $I_{C} = 20A, T_{J} = 25^{\circ}C$ $V_{IN} = 5V \leftrightarrow 0V, Inductive Load$ (High, Low-side)		-	0.35	-	us
	t <sub>C(ON)</sub>			-	0.16	-	us
	t <sub>OFF</sub>			-	0.75	-	us
	t <sub>C(OFF)</sub>	(high, Low-side)		-	0.23	-	us
	t <sub>rr</sub>	(Note 4)		-	0.13	-	us
Collector - Emitter Leakage Current	I <sub>CES</sub>	$V_{CE} = V_{CES}, T_J = 25^{\circ}C$		-	-	250	μA

Note:

4.  $t_{ON}$  and  $t_{OFF}$  include the propagation delay time of the internal drive IC.  $t_{C(ON)}$  and  $t_{C(OFF)}$  are the switching time of IGBT itself under the given gate driving condition internally. For the detailed information, please see Fig. 4.

FSAM20SH60A



FSAM20SH60A

#### **Control Part** Item Symbol Condition Min. Тур. Max. Unit Quiescent V<sub>CC</sub> Supply Cur- $V_{CC} = 1\overline{5V}$ $V_{CC(L)} - COM_{(L)}$ 26 mΑ IQCCL rent $IN_{(UL, VL, WL)} = 5V$ V<sub>CC</sub> = 15V V<sub>CC(UH)</sub>, V<sub>CC(VH)</sub>, V<sub>CC(WH)</sub> --130 uA **I**QCCH \_ COM<sub>(H)</sub> $IN_{(UH, VH, WH)} = 5V$ V<sub>BS</sub> = 15V $\begin{array}{l} \mathsf{V}_{\mathsf{B}(\mathsf{U})} \text{ - } \mathsf{V}_{\mathsf{S}(\mathsf{U})}, \, \mathsf{V}_{\mathsf{B}(\mathsf{V})} \text{ - } \mathsf{V}_{\mathsf{S}(\mathsf{V})}, \\ \mathsf{V}_{\mathsf{B}(\mathsf{W})} \text{ - } \, \mathsf{V}_{\mathsf{S}(\mathsf{W})} \end{array}$ Quiescent V<sub>BS</sub> Supply Cur-420 uA IQBS \_ \_ $IN_{(UH, VH, WH)} = 5V$ rent $V_{SC}$ = 0V, $V_{FO}$ Circuit: 4.7k $\Omega$ to 5V Pull-up Fault Output Voltage $V_{FOH}$ 4.5 --V $V_{SC}$ = 1V, $V_{FO}$ Circuit: 4.7k $\Omega$ to 5V Pull-up V V<sub>FOL</sub> -1.1 Short-Circuit Trip Level V<sub>CC</sub> = 15V (Note 5) V 0.45 0.51 0.56 V<sub>SC(ref)</sub> Sensing Voltage $R_{SC}$ = 50 $\Omega$ , $R_{SU}$ = $R_{SV}$ = $R_{SW}$ = 0 $\Omega$ and $I_{C}$ = 30A 0.45 0.51 0.56 V VSEN of IGBT Current (Note Fig. 7) Detection Level Supply Circuit Under-UV<sub>CCD</sub> 11.5 12 12.5 V Voltage Protection V UV<sub>CCR</sub> Reset Level 12 12.5 13 UV<sub>BSD</sub> Detection Level 7.3 9.0 10.8 V 8.6 10.3 V UV<sub>BSR</sub> Reset Level 12 C<sub>FOD</sub> = 33nF (Note 6) Fault Output Pulse Width 1.4 1.8 2.0 t<sub>FOD</sub> ms V **ON** Threshold Voltage High-Side Applied between IN<sub>(UH)</sub>, IN<sub>(VH)</sub>, \_ 0.8 V<sub>IN(ON)</sub> \_ IN(WH) - COM(H) **OFF** Threshold Voltage 3.0 V V<sub>IN(OFF)</sub> -\_ **ON** Threshold Voltage V<sub>IN(ON)</sub> Low-Side Applied between IN(UL), IN(VL), 8.0 V --OFF Threshold Voltage IN<sub>(WL)</sub> - COM<sub>(L)</sub> 3.0 V VIN(OFF) \_ Resistance of Thermistor @ T<sub>TH</sub> = 25°C (Note Fig. 6) (Note 7) 50 kΩ R<sub>TH</sub> \_ \_ @ T<sub>TH</sub> = 100°C (Note Fig. 6) (Note 7) 3.4 kΩ

Electrical Characteristics (T<sub>J</sub> = 25°C, Unless Otherwise Specified)

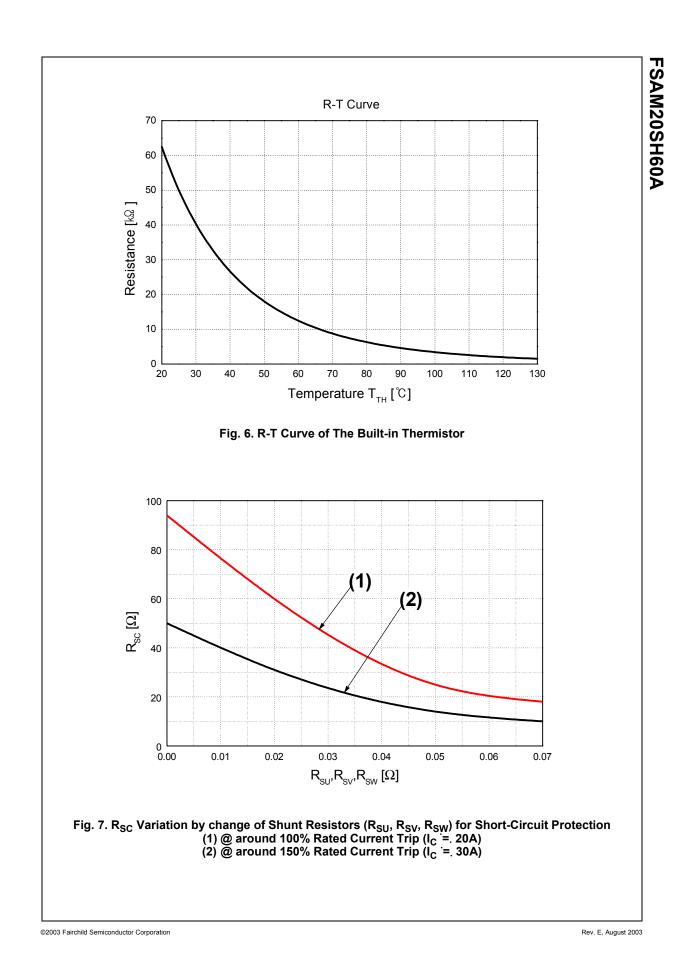
Note:

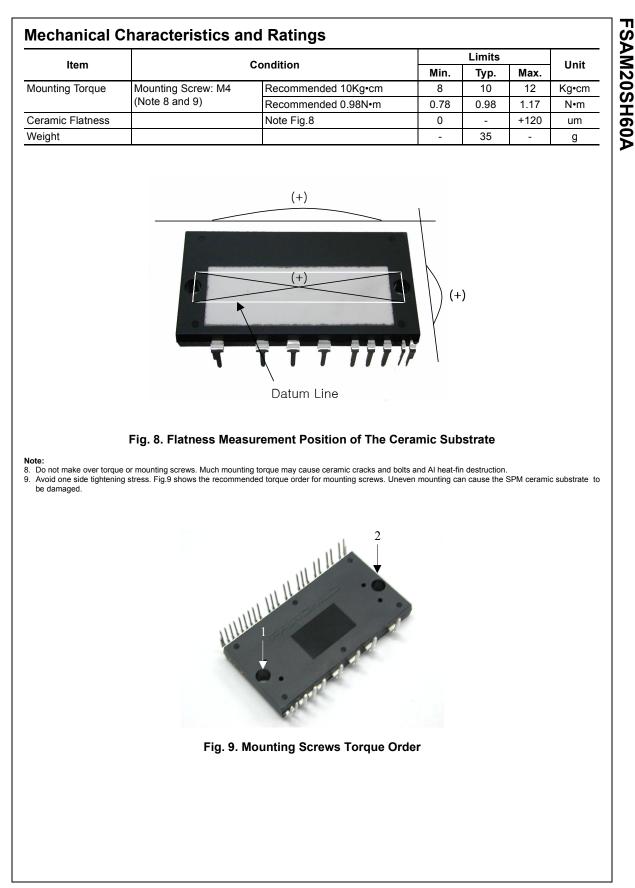
5. Short-circuit current protection is functioning only at the low-sides. It would be recommended that the value of the external sensing resistor ( $R_{SC}$ ) should be selected around 50  $\Omega$  in order to make the SC trip-level of about 30A at the shunt resistors ( $R_{SU}$ ,  $R_{SV}$ ,  $R_{SW}$ ) of  $\Omega\Omega$ . For the detailed information about the relationship between the external sensing resistor ( $R_{SC}$ ) and the shunt resistors ( $R_{SU}$ ,  $R_{SV}$ ,  $R_{SW}$ ), please see Fig. 7.

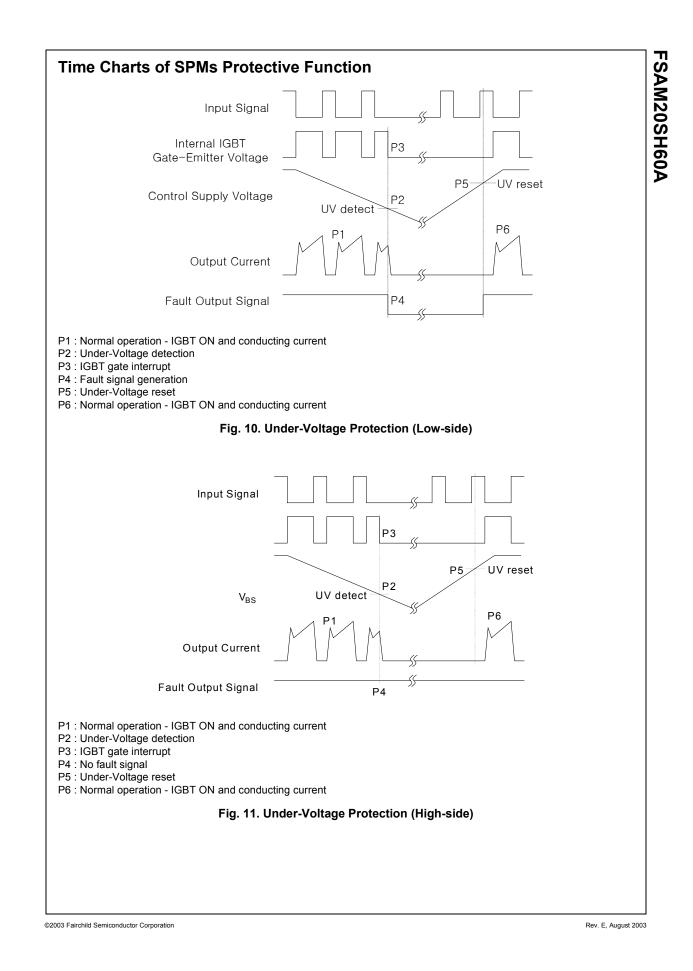
6. The fault-out pulse width  $t_{FOD}$  depends on the capacitance value of  $C_{FOD}$  according to the following approximate equation :  $C_{FOD}$  = 18.3 x 10<sup>-6</sup> x  $t_{FOD}[F]$ 7.  $T_{TH}$  is the temperature of thermistor itself. To know case temperature ( $T_{C}$ ), please make the experiment considering your application.

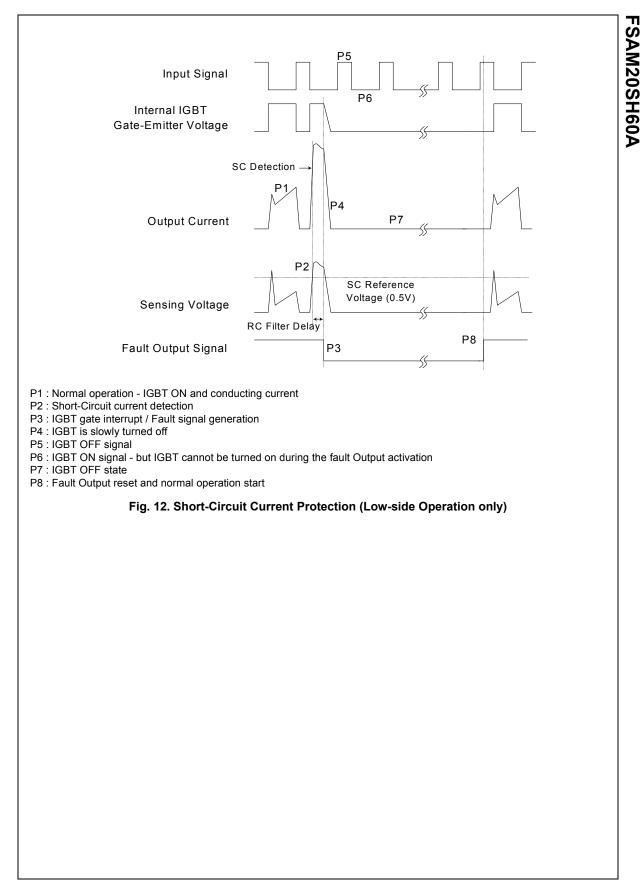
## **Recommended Operating Conditions**

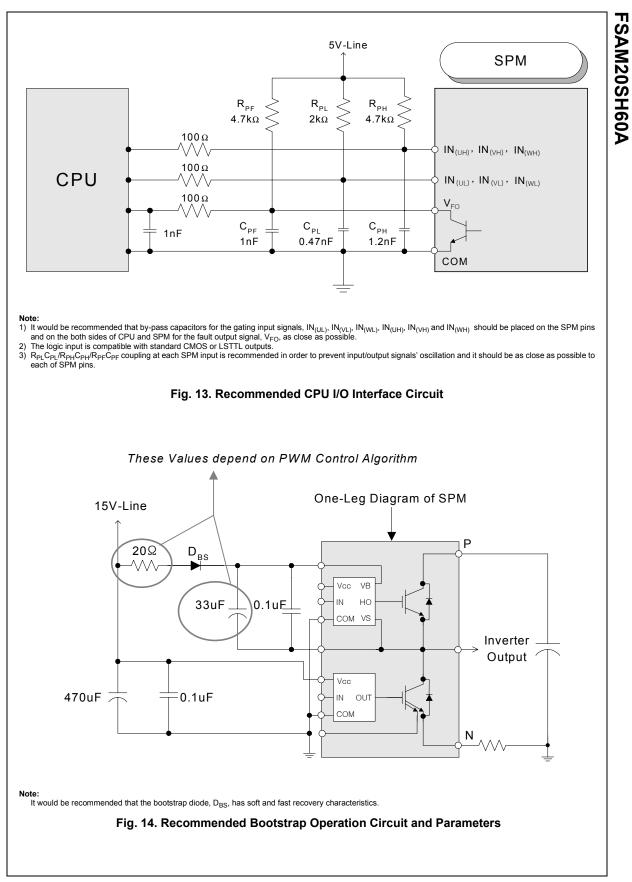
ltem	Querra ha a l			Values		
ltem	Symbol Condition		Min.	Тур.	Max.	Unit
Supply Voltage	V <sub>PN</sub>	Applied between P - N <sub>U</sub> , N <sub>V</sub> , N <sub>W</sub>	-	300	400	V
Control Supply Voltage	V <sub>CC</sub>	Applied between $V_{CC(UH)}$ , $V_{CC(VH)}$ , $V_{CC(WH)}$ - 1 COM <sub>(H)</sub> , $V_{CC(L)}$ - COM <sub>(L)</sub>		15	16.5	V
High-side Bias Voltage	V <sub>BS</sub>	Applied between $V_{B(U)}$ - $V_{S(U)}$ , $V_{B(V)}$ - $V_{S(V)}$ , $V_{B(W)}$ - $V_{S(W)}$	13.5	15	16.5	V
Blanking Time for Preventing Arm-short	t <sub>dead</sub>	For Each Input Signal		-	-	us
PWM Input Signal	f <sub>PWM</sub>	$T_C \le 100^{\circ}C, T_J \le 125^{\circ}C$	-	15	-	kHz
Input ON Threshold Voltage	V <sub>IN(ON)</sub>	$\begin{array}{l} \mbox{Applied between IN}_{(UH)}, \mbox{IN}_{(VH)}, \mbox{IN}_{(WH)} - \\ \mbox{COM}_{(H)}, \mbox{IN}_{(UL)}, \mbox{IN}_{(VL)}, \mbox{IN}_{(WL)} - \mbox{COM}_{(L)} \end{array}$		0 ~ 0.65	5	V
Input OFF Threshold Voltage	V <sub>IN(OFF)</sub>	(II)         (UL)         (WL)         (L)           Applied between $IN_{(UH)}$ , $IN_{(VH)}$ , $IN_{(WH)}$ -         4 ~ 5.5 $COM_{(H)}$ , $IN_{(UL)}$ , $IN_{(VL)}$ , $IN_{(WL)}$ - $COM_{(L)}$			V	

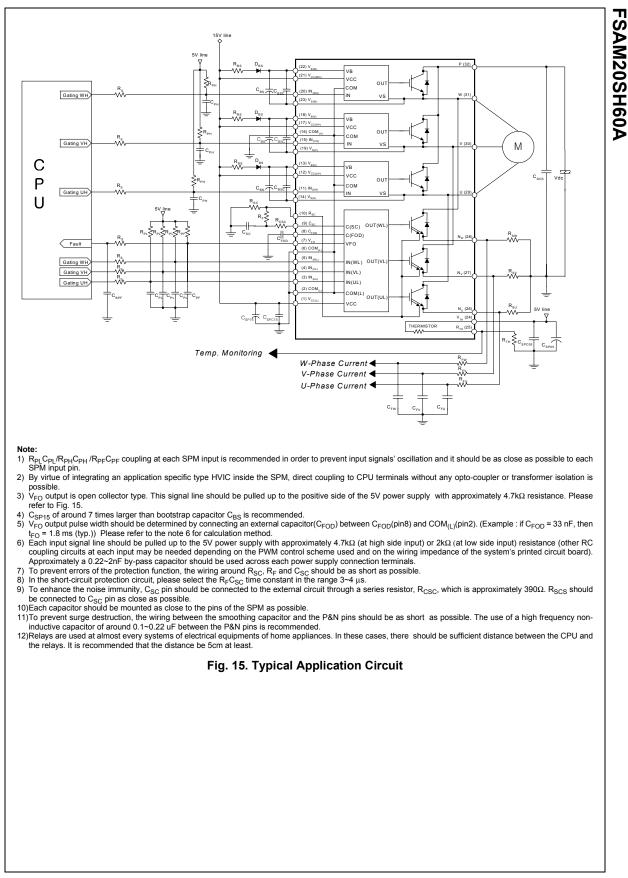


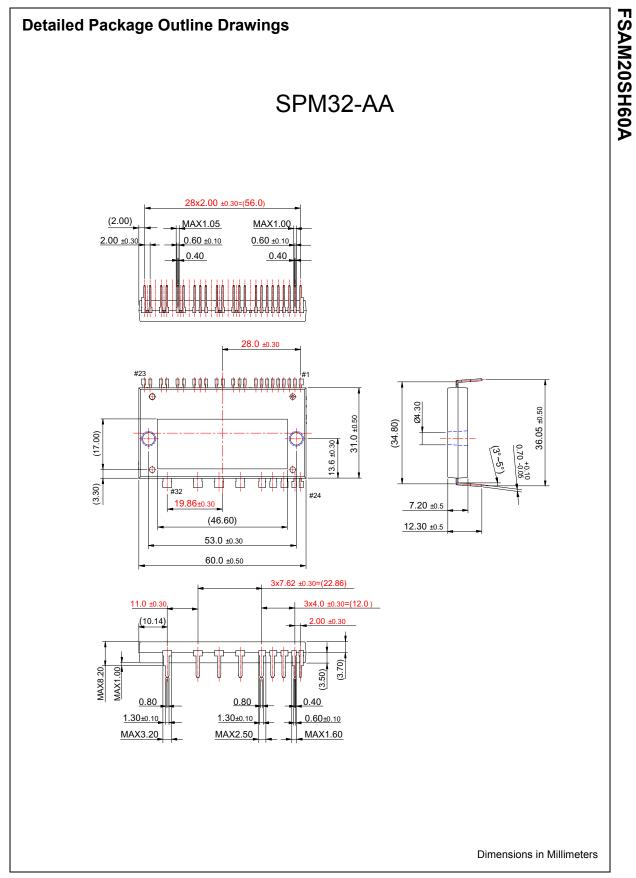












### TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEx™	FACT Quiet Series™	LittleFET™	Power247™	SuperSOT™-6
ActiveArray™	FAST®	MICROCOUPLER™	PowerTrench <sup>®</sup>	SuperSOT™-8
Bottomless™	FASTr™	MicroFET™	QFET <sup>®</sup>	SyncFET™
CoolFET™	FRFET™	MicroPak™	QS™	TinyLogic <sup>®</sup>
CROSSVOLT™	GlobalOptoisolator™	MICROWIRE™	QT Optoelectronics <sup>™</sup>	TINYOPTO™
DOME™	GTO™່	MSX™	Quiet Series <sup>™</sup>	TruTranslation™
EcoSPARK™	HiSeC™	MSXPro™	RapidConfigure™	UHC™
E <sup>2</sup> CMOS <sup>™</sup>	I²C™	OCX™	RapidConnect™	UltraFET <sup>®</sup>
EnSigna™	ImpliedDisconnect™	OCXPro™	SILENT SWITCHER®	VCX™
FACT™	ISOPLANAR™	<b>OPTOLOGIC<sup>®</sup></b>	SMART START™	
Across the boar	d. Around the world.™	OPTOPLANAR™	SPM™	
The Power Fran		PACMAN™	Stealth™	
Programmable A		POP™	SuperSOT™-3	

#### DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user. 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

#### PRODUCT STATUS DEFINITIONS

Definition of Terms

Product Status	Definition
Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.
	Formative or In Design First Production Full Production